LORLIN[®] TEST SYSTEMS

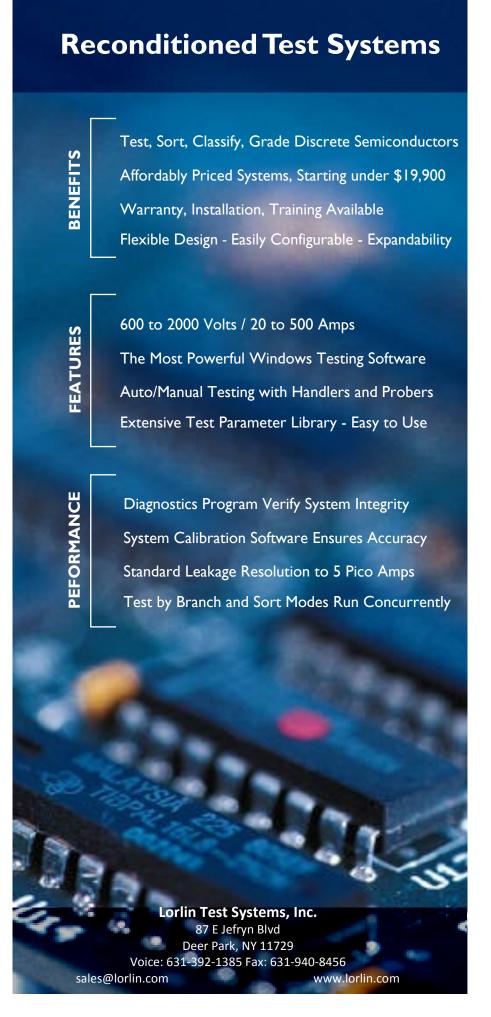


Lorlin Reconditioned Impact Series Test Systems check and verify the critical parameters of Small Signal and Power Discrete Semiconductors with a maximum degree of accuracy, yielding repeatable results and ensuring the highest confidence level attainable.

Lorlin Reconditioned Systems start under \$19,900 depending on the configuration and requirements. The Lorlin Windows Software is by far the most powerful and functional tool offering the user complete control over the desired test selections, options, sorting, binning, screening and numerous data reporting methods.

Lorlin also offers custom design engineering services, solutions and integration of many types of external equipment to meet your needs. The high performance reconditioned systems offer easy to use Windows for test routine creation, operation, and data views.

Transistors IGBTs Diodes Rectifiers Bridges Zeners Daarlingtons FETs MOSFETs JFETS SCRs Triacs Optos Arrays Small Signal Power Devices Hybrid Modules Dual, Quad and Octal



LORLIN® TEST SYSTEMS



Lorlin Reconditioned Testers can be configured for most all applications offering cost effective test solutions with high performance results.

The test system can be used for incoming inspection, quality assurance, high reliability, component characterization, final test, and wafer probe.

System measurement techniques, refined and proven by over 50 years combined with the most powerful software in the industry make Lorlin Test Systems a perfect choice.

Contact us Today for Pricing and Information



The Most Advanced Discrete Test Systems Available



- 1. Accuracy does not include the tag error and vary on test performed.
- 2. Higher ranges may affect resolution and accuracy specifications.
- 3. Requires an external high voltage and/or high current supply

Reconditioned Systems

System Specifications			
FEATURE	RANGE	RESOLUTION	ACCURACY
Voltage Measurements	0-600 V 600-2000 V ²	0.5 mV	0.5% '
Current Measurements	0-20 A 20-500A ²	5 pA	0.5% '
Expands to 5 Test Stations and PCs	Rack Mounted, and Desktop	N/A	N/A
High Voltage/High Current Multiplex X4	2000 Volts 200 Amps	See Above	See Above

Test Parameters

TEST TYPE	TYPICAL PARAMETERS	
Leakage	IR, ICE(O,S,V,R,X), IEBO, IC IDGO, IGSO, IDSO (O,S,R,X,V), IGSS, IGV, IGDO, IDSX, ISDX, ISVI, IGI, VGSI, VTHI	
Breakdown	BVCBO, BVEBO, BVCE(O, S, V, R, X) ² BVR, BVZ, BVDGO, BVGSO, BVDS (O,S,R,X,V)	
On State	HFE IB, HFE, DHFE, VCESAT, VBESAT, VBEF, VBCF, VRE, VBEON, VF, VZ, VGSF, VGDF, VGS, VDS, VDSON, RDSON, IDON, VTH, ZZ(T,K)	
Gain	HFE, I+HFE IB, DHFE, AC I + HFE, AC HIB, GM	
Scr/Triac	IAKR, IAKF, IGKO, BVAKR, IH, BVAKF, BVGKO, IGT, VGT, TH, IL, VON	
System and Standard Options		

PRODUCT DESCRIPTION MODEL OPTIONAL COMMENTS

Double Impact Systems RACK PC AND Up to 5 Stations Double Impact Base System DI-700 VIDEO CONSOLE and PCs OTS-100 Standard Station 600V/20A 100 A³ Requires Supply HVS-102 100A³ 2 KV Station with Built In Supply Requires Supply HCS-500 500A OTS-340 400A 200 A Station with Built In Supply OTS-300 OTS-201 2KV Multiplex Test Station 100 A Requires Supply³ OTS-221 160-200 A Requires Supply³ Up to 4 per System FET-101 Power Fet Option 80 V Gate Supply Plug In Option Scr/Triac Option SCR-100 User Adjustable Plug In Option 'High Voltage Supply HVS-201 High Voltage Supply, Multiplexes to 4 Stations HCM-201 High Current Supply, Multiplexes to 4 Stations ²High Current Supply

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